| FORM PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | ATTY. DOCKET NO. 71247-0064 | SERIAL NO. 10/589,137 |
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| | LIST OF REFERENCES CITED BY APPLICANT | APPLICANT Chouki AKTOUF | |
| | *(Use several sheets if necessary)* | FILING DATE 08/07/2008 | GROUP ART UNIT 2825 |

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.